

### K3534-VB Datasheet

## N-Channel 900 V (D-S) Super Junction Power MOSFET

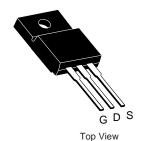
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	900	)			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V	1.2			
Q <sub>g</sub> (Max.) (nC)	200				
Q <sub>gs</sub> (nC)	24				
Q <sub>gd</sub> (nC)	110				
Configuration	Single				

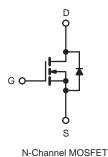
#### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC









ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			$V_{DS}$	900	V		
Gate-Source Voltage			$V_{GS}$	± 20	7 °		
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	I <sub>D</sub>	5 3.9	А		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	21			
Linear Derating Factor				1.5	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	770	mJ		
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	7.8	Α		
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ		
Maximum Power Dissipation $T_C = 25  ^{\circ}C$			$P_{D}$	190	W		
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	2.0	V/ns		
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>	7		
Manustina Tanana	6-32 or M3 screw			10	lbf ⋅ in		
Mounting Torque				1.1	N⋅m		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=23 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=7.8$  A (see fig. 12). c.  $I_{SD}\leq 7.8$  A, dl/dt  $\leq 140$  A/µs,  $V_{DD}\leq 600$  V,  $T_J\leq 150$  °C. d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40	
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.65	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> :	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current		V <sub>DS</sub> :	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V		-	100	μΑ
Zero date voltage Brain ourient	ate Voltage Drain Current $I_{DSS}$ $V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$		$V, V_{GS} = 0 V, T_{J} = 125  ^{\circ}C$	-	-	500	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	$I_D = 3.7 A^b$	-	1.2	-	Ω
Forward Transconductance	9fs	V <sub>DS</sub> =	= 100 V, I <sub>D</sub> = 3.7 A <sup>b</sup>	5.6	-	-	S
Dynamic							
Input Capacitance	$C_{iss}$	V <sub>GS</sub> = 0 V,		-	3100	-	pF
Output Capacitance	C <sub>oss</sub>		$V_{DS} = 25 \text{ V},$		800	-	
Reverse Transfer Capacitance	$C_{rss}$	f = 1.0 MHz, see fig. 5		-	490	-	
Total Gate Charge	$Q_g$		I <sub>D</sub> = 3.8 A, V <sub>DS</sub> = 400 V, see fig. 6 and 13 <sup>b</sup>	-	-	200	nC
Gate-Source Charge	$Q_gs$	V <sub>GS</sub> = 10 V		-	-	24	
Gate-Drain Charge	$Q_gd$			-	-	110	
Turn-On Delay Time	$t_{d(on)}$			-	19	-	- - ns
Rise Time	t <sub>r</sub>	V <sub>DD</sub> =	$V_{DD} = 400 \text{ V, } I_{D} = 3.8 \text{ A,} \ R_{g} = 6.2 \ \Omega, \ R_{D} = 52 \ \Omega \ \text{see fig. } 10^{b}$		38	-	
Turn-Off Delay Time	$t_{d(off)}$	R <sub>g</sub> =			120	-	
Fall Time	t <sub>f</sub>	335 ng. 10		-	39	-	
Internal Drain Inductance	$L_{D}$	6 mm (0.25")	Between lead, 6 mm (0.25") from		5.0	-	الم
Internal Source Inductance	L <sub>S</sub>	package and center of die contact		-	13	-	- nH
Drain-Source Body Diode Characteristic	s	•				•	
Continuous Source-Drain Diode Current	Is	MOSFET sym	MOSFET symbol showing the		-	5.0	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	21	- A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 3.8 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T. =	$T_J = 25 \text{ °C}, I_F = 3.8 \text{ A},$		650	980	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$J = 25$ C, $I_F = 3.6$ A, $I_F = 3$		-	3.8	5.7	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L				Ln)	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

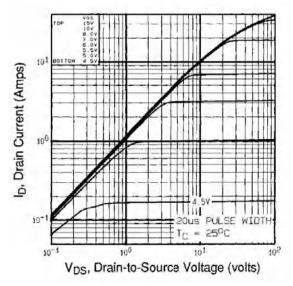


Fig. 1 - Typical Output Characteristics,  $T_C$  = 25 °C

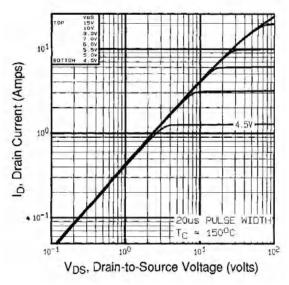


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

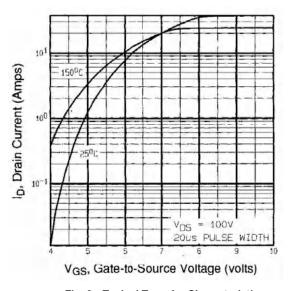


Fig. 3 - Typical Transfer Characteristics

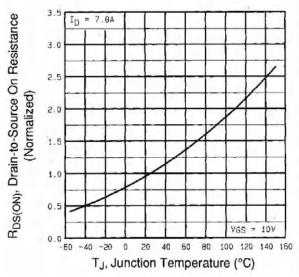


Fig. 4 - Normalized On-Resistance vs. Temperature



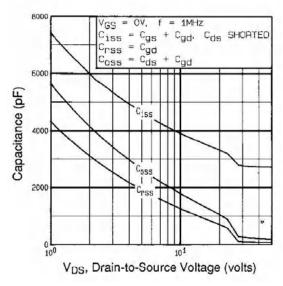


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

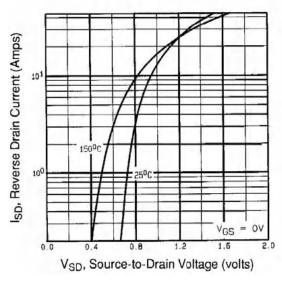


Fig. 7 - Typical Source-Drain Diode Forward Voltage

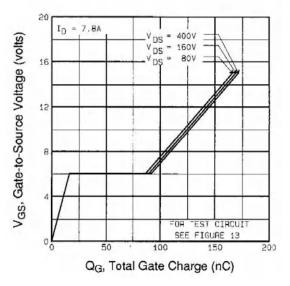


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

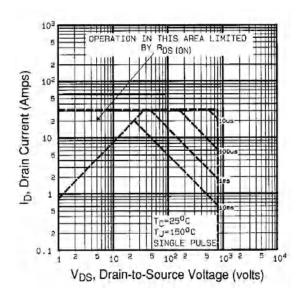


Fig. 8 - Maximum Safe Operating Area



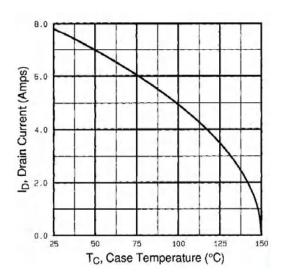


Fig. 9 - Maximum Drain Current vs. Case Temperature

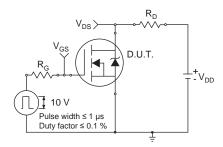


Fig. 10a - Switching Time Test Circuit

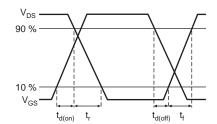


Fig. 10b - Switching Time Waveforms

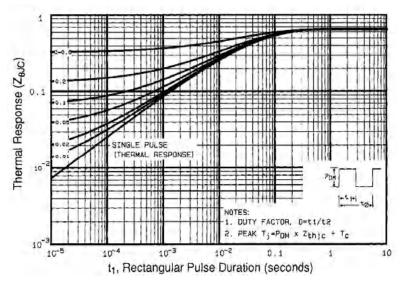


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



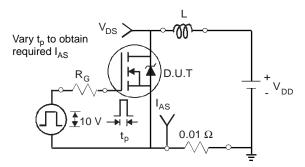


Fig. 12a - Unclamped Inductive Test Circuit

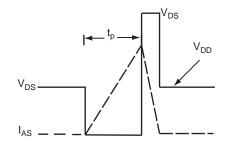


Fig. 12b - Unclamped Inductive Waveforms

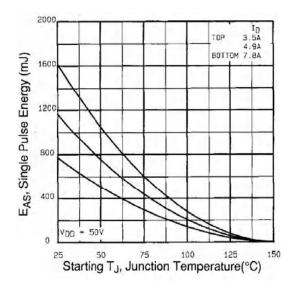


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

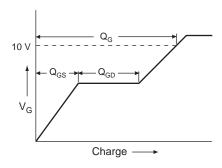


Fig. 13a - Basic Gate Charge Waveform

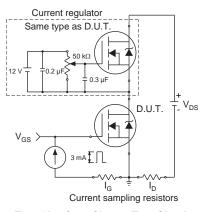
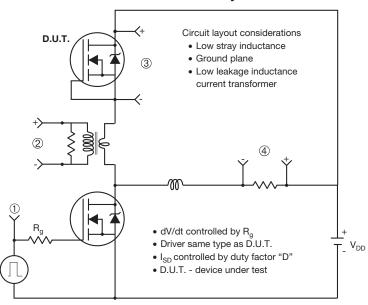


Fig. 13b - Gate Charge Test Circuit



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#### Peak Diode Recovery dV/dt Test Circuit



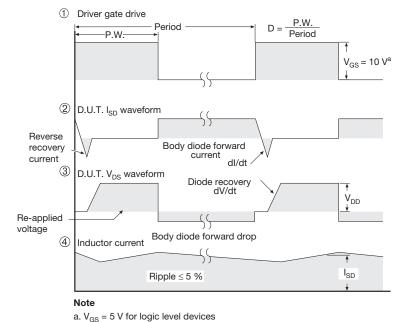
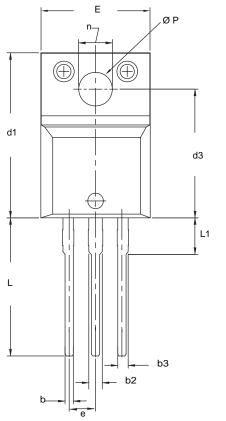
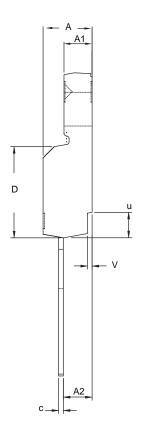


Fig. 14 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**





DIM.	MILLIN	METERS	INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
  These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
  All critical dimensions should C meet C<sub>pk</sub> > 1.33.
  All dimensions include burrs and plating thickness.
  No chipping or package damage.



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